

Search Notes**Application/Control No.**

10/525,410

Examiner

Karen Cheng

Applicant(s)/Patent under Reexamination

FENG ET AL.

Art Unit

1626

SEARCHED

Class	Subclass	Date	Examiner
548	311.1	1/4/2007	KC
548	315.4	1/4/2007	KC
548	347.1	1/4/2007	KC
548	355.1	1/4/2007	KC
549	429	1/4/2007	KC
549	460	1/4/2007	KC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN Structure Search (see attached)	1/4/2007	KC
EAST Search (see attached)	1/4/2007	KC
Inventor Name Search	1/4/2007	KC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner